

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
29	BRS	23	((volume\$5 or voxel) same (slic\$4 or (cross adj section\$4))) same imag\$4) and ((slic\$4 or (cross adj section\$4)) near7 (centroid))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/17 17:25		
30	BRS	2102	382/141,144-150,284.ccls.	USPAT	2004/09/20 18:42		
31	BRS	19900	(die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or imag\$4)	USPAT	2004/09/20 18:45		
32	BRS	21128	(die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or imag\$4)	USPAT	2004/09/20 18:45		
33	BRS	7521	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6))))	USPAT	2004/09/20 19:06		
34	BRS	1619	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4	USPAT	2004/09/20 19:05		
35	BRS	3	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4) and 382/284.ccls.	USPAT	2004/09/20 18:50		
36	BRS	2	382/141,144-150.ccls. and 382/284.ccls.	USPAT	2004/09/20 18:51		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
37	BRS	28135	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 20:59		
38	BRS	4773	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:06		
39	BRS	28135	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:06		
40	BRS	4773	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:23		
41	BRS	564	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4) and (image near3 (composite or entire or whole))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:07		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
42 BRS	99	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4) and (image near3 (composite))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:07		
43 BRS	146	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4) same (image near3 (composite or entire or whole))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:07		
44 BRS	16	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4) same (image near3 (composite))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:08		
45 IS&R	4	((("6753972") or ("5301248") or ("5973777") or ("6072899")).PN.	USPAT	2004/09/20 19:14		
46 BRS	4	((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4) and 382/284.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:32		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
47 BRS	16	((((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4) and 382/284,294.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:32		